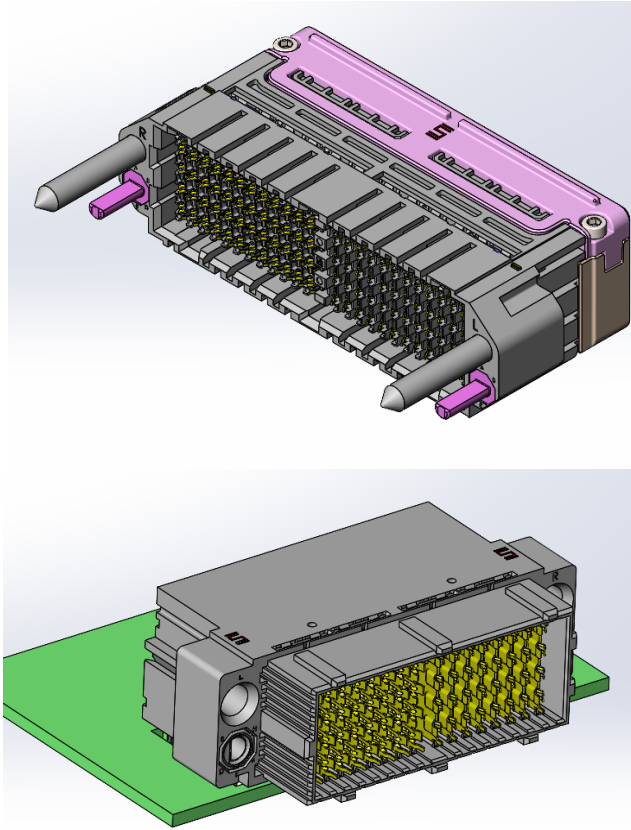




Project: Design Qualification Test Report	Tracking Code: CR-1169107_Report_Rev_1
Requested by: Tyler Lang	Date: 7/9/2025
Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X	
Part description: NVCF / NVBM	Tech: Tony Wagoner
Test Start: 1/10/2025	Test Completed: 4/15/2025



DESIGN QUALIFICATION TEST REPORT
NVCF / NVBM
NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X

Tracking Code: CR-1169107_Report_Rev_1	Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X
Part description: NVCF / NVBM	

REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
5/12/2025	1	Initial test	PC

Tracking Code: CR-1169107_Report_Rev_1	Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X
Part description: NVCF / NVBM	

CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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SCOPE

To perform the following tests: Design Qualification test. Please see test plan.

APPLICABLE DOCUMENTS

Standards: EIA Publication 364

TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR and DWV/IR testing were cleaned according to CO-SC-WI-3029.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR and DWV/IR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Samtec Test PCBs used: PCB-114020-TST-XX/PCB-114021-TST-XX/PCB-113995-TST-XX / PCB-114030-TST-XX.

FLOWCHARTS

Gas Tight

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

8 Assemblies

*Note: HDR with 6" Cable w/ End 2 PCB**Note: 100% LLCR*

Step	Description
1.	LLCR ⁽²⁾
2.	Gas Tight ⁽¹⁾
3.	LLCR ⁽²⁾ Max Delta = 15 mOhm

 (1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

Thermal Aging

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

8 Assemblies

*Note: HDR with 6" Cable w/ End 2 PCB**Note: 100% LLCR*

Step	Description
1.	Contact Gaps
2.	Mating/Unmating Force ⁽²⁾
3.	LLCR ⁽¹⁾
4.	Thermal Age ⁽³⁾
5.	LLCR ⁽¹⁾ Max Delta = 15 mOhm
6.	Mating/Unmating Force ⁽²⁾
7.	Contact Gaps

 (1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

FLOWCHARTS Continued

Mating/Unmating/Durability

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

8 Assemblies

Note: HDR with 6" Cable w/ End 2 PCB

Note: 100% LLCR

Step	Description
1.	Contact Gaps
2.	LLCR ⁽²⁾
3.	Mating/Unmating Force ⁽³⁾
4.	Cycles Quantity = 25 Cycles
5.	Mating/Unmating Force ⁽³⁾
6.	Cycles Quantity = 25 Cycles
7.	Mating/Unmating Force ⁽³⁾
8.	Cycles Quantity = 25 Cycles
9.	Mating/Unmating Force ⁽³⁾
10.	Cycles Quantity = 25 Cycles
11.	Mating/Unmating Force ⁽³⁾
12.	Contact Gaps
13.	LLCR ⁽²⁾ Max Delta = 15 mOhm
14.	Thermal Shock ⁽⁴⁾ - Non Standard
15.	LLCR ⁽²⁾ Max Delta = 15 mOhm
16.	Humidity ⁽¹⁾
17.	LLCR ⁽²⁾ Max Delta = 15 mOhm
18.	Mating/Unmating Force ⁽³⁾

(1) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = Other

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-40°C to +85°C)

Test Duration = A-3 (100 Cycles)

Cable Rating

FLOWCHARTS Continued

IR/DWV

Note: 12" Double Ended Cable

Note: DWV = 450V Test Voltage

Note: IR = 100V Test Voltage

Pin-to-Pin

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
2 Assemblies

Row-to-Row

Group 2

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
2 Assemblies

Pin-to-Ground

Group 3

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
2 Assemblies

Step	Description	Step	Description	Step	Description
1.	IR (3) - Non Standard	1.	IR (3) - Non Standard	1.	IR (3) - Non Standard
2.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	2.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	2.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V
3.	Thermal Shock (4) - Non Standard	3.	Thermal Shock (4) - Non Standard	3.	Thermal Shock (4) - Non Standard
4.	IR (3) - Non Standard	4.	IR (3) - Non Standard	4.	IR (3) - Non Standard
5.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	5.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	5.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V
6.	Humidity (2)	6.	Humidity (2)	6.	Humidity (2)
7.	IR (3) - Non Standard	7.	IR (3) - Non Standard	7.	IR (3) - Non Standard
8.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	8.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V	8.	DWV at Test Voltage ⁽¹⁾ Test Voltage = 450 V

- (1) DWV at Test Voltage = EIA-364-20
Test Condition = 1 (Sea Level)
DWV test voltage is equal to 75% of the lowest breakdown voltage
Test voltage applied for 60 seconds
- (2) Humidity = EIA-364-31
Test Condition = B (240 Hours)
Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)
Test Exceptions: ambient pre-condition and delete steps 7a and 7b
- (3) IR = Other
Test Condition = 100 Vdc, 2 Minutes Max
- (4) Thermal Shock = Other
Exposure Time at Temperature Extremes = 1/2 Hour
Method A, Test Condition = I (-40°C to +85°C)
Test Duration = A-3 (100 Cycles)
Cable Rating

FLOWCHARTS Continued

Current Carrying Capacity

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
1 Pins Powered
Signal

Note: 12" Double Ended Cable

Step	Description
1.	CCC ⁽¹⁾ Rows = 1 Number of Positions = 1 <i>Note: Center of connector location</i>

Group 2

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
8 Pins Powered
Power

Note: 12" Double Ended Cable

Step	Description
1.	CCC ⁽¹⁾ Rows = 8 Number of Positions = 1 <i>Note: All signal pins combined carry supply while all grounds on that wafer carry return</i>

(1) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

Mechanical Shock/Random Vibration/LLCR

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
8 Assemblies

Note: HDR 12" Cable w/ End 2 PCB
Note: 100% LLCR

Step	Description
1.	LLCR ⁽¹⁾
2.	Mechanical Shock ⁽²⁾
3.	Random Vibration ⁽³⁾
4.	LLCR ⁽¹⁾ Max Delta = 15 mOhm

Group 2

NVCF-DP-16-V-3-XX-X-X-X-X-1
NVBM-DP-16-RA-S-2-X-X
8 Assemblies
MIL-STD-810G_CHG-1

Note: HDR 12" Cable w/ End 2 PCB
Note: 100% LLCR

Step	Description
1.	LLCR ⁽¹⁾
2.	Mechanical Shock ⁽²⁾
3.	Random Vibration ⁽⁴⁾ - Non Standard
4.	LLCR ⁽¹⁾ Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

(4) Random Vibration = Other

MIL-STD-810G_CHG-1; Method = 514.7, Annex C, Category 4 (Common Carrier); 1hr per axis

FLOWCHARTS Continued

Mechanical Shock/Random Vibration/Event Detection

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

60 Points

Note: 12" Double Ended Cable

Step	Description
------	-------------

- | | |
|----|---|
| 1. | Nanosecond Event Detection
(Mechanical Shock) ⁽¹⁾ |
| 2. | Nanosecond Event Detection
(Random Vibration) ⁽²⁾ |

(1) Nanosecond Event Detection (Mechanical Shock)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-27 for Mechanical Shock:

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)

Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)

Use EIA-364-87 for Nanosecond Event Detection:

Test Condition = F (50 nanoseconds at 10 ohms)

Use EIA-364-28 for Random Vibration:

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

Cable Pull

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

5 Assemblies

0 Degrees

Note: 16" Double Ended Cable

Step	Description
------	-------------

- | | |
|----|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |
|----|---------------------------|

Group 2

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

5 Assemblies

90 Degrees - Lateral

Note: 16" Double Ended Cable

Step	Description
------	-------------

- | | |
|----|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |
|----|---------------------------|

Group 3

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

5 Assemblies

90 Degrees - Transverse

Note: 16" Double Ended Cable

Step	Description
------	-------------

- | | |
|----|---------------------------|
| 1. | Cable Pull ⁽¹⁾ |
|----|---------------------------|

(1) Cable Pull = EIA-364-38

Measure and Record Force Required to Failure

Failure = Discontinuity >1 microsecond at 10 ohms

FLOWCHARTS Continued

Cable Flex

Note: Use Different Samples for Each Group

Group 1

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

8 Assemblies

Circular Cable (Lateral)

*Note: Use DWV Breakdown from
IR/DWV Sequence*

Note: 16" Double Ended Cable

Note: Use Mandrel 1.25"

Group 2

NVCF-DP-16-V-3-XX-X-X-X-X-1

NVBM-DP-16-RA-S-2-X-X

8 Assemblies

Circular Cable (Transverse)

*Note: Use DWV Breakdown from
IR/DWV Sequence*

Note: 16" Double Ended Cable

Note: Use Mandrel 3.75"

Step	Description	Step	Description
1.	IR ₍₃₎	1.	IR ₍₃₎
2.	DWV at Test Voltage ₍₂₎	2.	DWV at Test Voltage ₍₂₎
3.	Cable Flex ₍₁₎	3.	Cable Flex ₍₁₎
4.	Visual Inspection	4.	Visual Inspection
5.	IR ₍₃₎	5.	IR ₍₃₎
6.	DWV at Test Voltage ₍₂₎	6.	DWV at Test Voltage ₍₂₎

(1) Cable Flex = EIA-364-41

Circular Jacket Cable - to be tested 90° each direction (180° total)

Flat Cable - to be tested 70° each direction (140° total)

Monitor continuity during flex testing

Failure = Discontinuity >1 microsecond at 10 ohms

(2) DWV at Test Voltage = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(3) IR = EIA-364-21

Test Condition = 500 Vdc, 2 Minutes Max

ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

THERMAL:

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition at 105° C.
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

THERMAL SHOCK:

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition I: -40°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

HUMIDITY:

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

MECHANICAL SHOCK (Specified Pulse):

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition G
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Sawtooth
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

VIBRATION:

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.10 G² / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

VIBRATION:

- 1) MIL-STD-810G_CHG-1; Method = 514.7, Annex C, Category 4 (Common Carrier); 1hr per axis

NANOSECOND-EVENT DETECTION:

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

MATING/UNMATING:

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of I^2R (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
 - a. Self-heating (resistive)
 - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at four temperature points are reported:
 - a. Ambient
 - b. 85° C
 - c. 95° C
 - d. 115° C
- 8) Typically, neighboring contacts (in close proximity to maximize heat buildup) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
 - a. $\leq +5.0$ mOhms:-----Stable
 - b. $+5.1$ to $+10.0$ mOhms:-----Minor
 - c. $+10.1$ to $+15.0$ mOhms:-----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms:-----Marginal
 - e. $+50.1$ to $+1000$ mOhms:-----Unstable
 - f. $>+1000$ mOhms:-----Open Failure
- 4) Procedure:
 - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
 - b. Test Conditions:
 - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
 - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
 - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
 - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
 - v. Exposure time, 55 to 65 minutes.
 - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
 - vii. The samples shall be dried after exposure for a minimum of 1 hour.
 - viii. Drying temperature 50° C
 - ix. The final LLCR shall be conducted within 1 hour after drying.

INSULATION RESISTANCE (IR):

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) PROCEDURE:
 - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
 - b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Electrification Time 2.0 minutes
 - iii. Test Voltage (100 VDC) corresponds to calibration settings for measuring resistances.
- 2) MEASUREMENTS:
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 1000 megohms.

Tracking Code: CR-1169107_Report_Rev_1	Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X
Part description: NVCF / NVBM	

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

1) PROCEDURE:

- a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
- b. Test Conditions:
 - i. Between Adjacent Contacts or Signal-to-Ground
 - ii. Barometric Test Condition 1
 - iii. Rate of Application 500 V/Sec
 - iv. Test Voltage (VAC) until breakdown occurs

2) MEASUREMENTS/CALCULATIONS

- a. The breakdown voltage shall be measured and recorded.
- b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
- c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

CABLE PULL:

- 1) Secure cable near center and pull on connector
 - a. At 0°, in-line with cable
 - b. At 90°, in-line with cable



Fig. 1

0° Connector pull



Fig. 2

90° Connector pull-Lateral

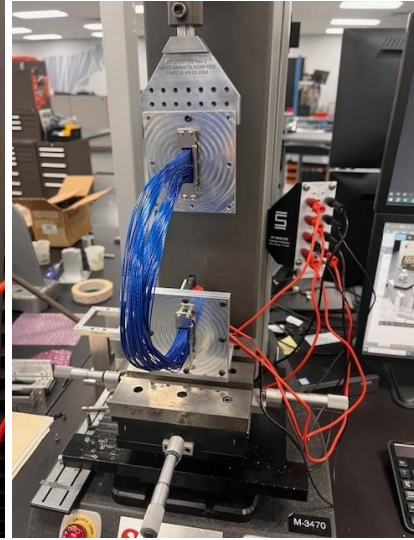


Fig. 3

90° Connector pull- Transverse

CABLE Flex:

- 1) Oscillate and monitor electrical continuity for open circuit indication.
 - a. $\pm 90^\circ$ Flex Mode, bend up to 100 cycles. load on 16 oz.

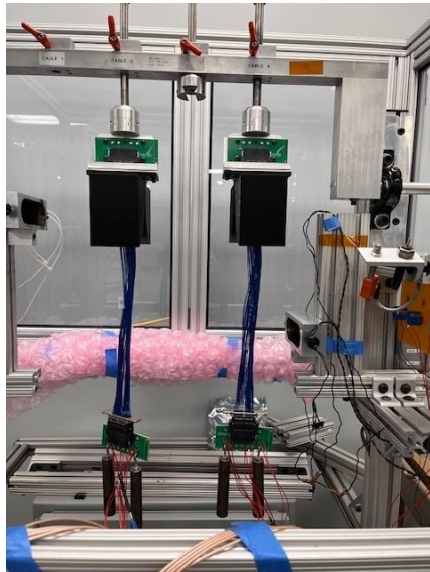


Fig. 4- Cable Flex-Lateral



Fig. 5- Cable Flex- Transverse

RESULTS

Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise-----1.5 A per contact with 1 contact (1 x 1) powered (Single contact rating limited by the cable type)
- CCC for a 30°C Temperature Rise-----9.0 A (1.1 Amps per Signal Pin) with All contacts (8x1) powered

Mating – Unmating Forces

Thermal Aging Group

- Initial
 - Mating
 - Min ----- 9.66 lbs
 - Max ----- 9.97 lbs
 - Unmating
 - Min ----- 6.98 lbs
 - Max ----- 8.50 lbs
- After Thermal
 - Mating
 - Min ----- 6.25 lbs
 - Max ----- 7.70 lbs
 - Unmating
 - Min ----- 5.88 lbs
 - Max ----- 6.76 lbs

RESULTS Continued

Mating/Unmating Durability Group

- **Initial**
 - **Mating**
 - Min ----- 9.00 lbs
 - Max-----10.01 lbs
 - **Unmating**
 - Min ----- 6.61 lbs
 - Max----- 7.50 lbs
- **After 25 Cycles**
 - **Mating**
 - Min ----- 9.30 lbs
 - Max-----10.31 lbs
 - **Unmating**
 - Min ----- 7.58 lbs
 - Max----- 8.17 lbs
- **After 50 Cycles**
 - **Mating**
 - Min ----- 9.81 lbs
 - Max-----10.77 lbs
 - **Unmating**
 - Min ----- 8.05 lbs
 - Max----- 8.62 lbs
- **After 75 Cycles**
 - **Mating**
 - Min -----10.18 lbs
 - Max-----11.26 lbs
 - **Unmating**
 - Min ----- 8.34 lbs
 - Max----- 8.88 lbs
- **After 100 Cycles**
 - **Mating**
 - Min -----10.59 lbs
 - Max-----11.86 lbs
 - **Unmating**
 - Min ----- 8.69 lbs
 - Max----- 9.24 lbs
- **After Humidity**
 - **Mating**
 - Min ----- 7.12 lbs
 - Max----- 7.54 lbs
 - **Unmating**
 - Min ----- 6.01 lbs
 - Max----- 6.32 lbs

RESULTS Continued

Cable Pull Force

0° Pull

- Min ----- 273.00 lbs
- Max ----- 317.80 lbs

90° Pull- Lateral

- Min ----- 395.80 lbs
- Max ----- 445.10 lbs

90° Pull- Transverse

- Min ----- 219.50 lbs
- Max ----- 222.10 lbs

Insulation Resistance minimums, IR

Pin to Pin

- Initial
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Thermal Shock
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Humidity
 - Mated ----- 2060 Meg Ω ----- Passed
 - Unmated ----- 3400 Meg Ω ----- Passed

Row to Row

- Initial
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Thermal Shock
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Humidity
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed

Pin to Ground

- Initial
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Thermal Shock
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 9000 Meg Ω ----- Passed
- Humidity
 - Mated ----- 9000 Meg Ω ----- Passed
 - Unmated ----- 1200 Meg Ω ----- Passed

RESULTS Continued

Dielectric Withstanding Voltage minimums, DWV

- Minimums
 - Breakdown Voltage-----600 VAC
 - Test Voltage-----450 VAC
 - Working Voltage-----150 VAC

Pin to Pin

- Initial DWV-----Passed
- Thermal DWV-----Passed
- Humidity DWV-----Passed

Row to Row

- Initial DWV-----Passed
- Thermal DWV-----Passed
- Humidity DWV-----Passed

Pin to Ground

- Initial DWV-----Passed
- Thermal DWV-----Passed
- Humidity DWV-----Passed

Cable Flex:

Lateral

Insulation Resistance minimums, IR

Pin to Pin

- Initial
 - Mated-----45000 Meg Ω -----Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω -----Passed

Row to Row

- Initial
 - Mated-----45000 Meg Ω -----Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω -----Passed

Pin To Ground

- Initial
 - Mated-----45000 Meg Ω -----Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω -----Passed

Dielectric Withstanding Voltage minimums, DWV

- Test Voltage-----450 VAC

Pin to Pin

- Initial DWV-----Passed
- After 100 Flex cycles DWV-----Passed

Row to Row

- Initial DWV-----Passed
- After 100 Flex cycles DWV-----Passed

Pin To Ground

- Initial DWV-----Passed
- After 100 Flex cycles DWV-----Passed

RESULTS Continued

Transverse

Pin to Pin

- Initial
 - Mated-----45000 Meg Ω ----- Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω ----- Passed

Row to Row

- Initial
 - Mated-----45000 Meg Ω ----- Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω ----- Passed

Pin To Ground

- Initial
 - Mated-----45000 Meg Ω ----- Passed
- After 100 flex cycles
 - Mated-----45000 Meg Ω ----- Passed

Dielectric Withstanding Voltage minimums, DWV

- Test Voltage-----450 VAC

Pin to Pin

- Initial DWV -----Passed
- After 100 Flex cycles DWV -----Passed

Row to Row

- Initial DWV -----Passed
- After 100 Flex cycles DWV -----Passed

Pin To Ground

- Initial DWV -----Passed
- After 100 Flex cycles DWV -----Passed

RESULTS Continued

LLCR Gas Tight (1152 LLCR test points)

Signal Pin

- Initial ----- 189.25 mOhms Max

Ground Pin

- Initial ----- 12.14 mOhms Max
- Gas-Tight
 - <= +5.0 mOhms ----- 1151 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 1 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure

LLCR Thermal Aging (576 LLCR test points)

Signal Pin

- Initial ----- 180.09 mOhms Max

Ground Pin

- Initial ----- 16.99 mOhms Max
- Thermal Aging
 - <= +5.0 mOhms ----- 456 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 118 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 2 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure

LLCR Durability (576 LLCR test points)

Signal Pin

- Initial ----- 179.72 mOhms Max

Ground Pin

- Initial ----- 12.76 mOhms Max
- Durability, 100 Cycles
 - <= +5.0 mOhms ----- 576 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure
- Thermal
 - <= +5.0 mOhms ----- 576 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure
- Humidity
 - <= +5.0 mOhms ----- 576 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure

RESULTS Continued

LLCR Shock & Vibration (576 LLCR test points)

Group 1

Signal Pin

- Initial -----331.61 mOhms Max

Ground Pin

- Initial ----- 17.20 mOhms Max
- Shock & Vibration
 - <= +5.0 mOhms -----559 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 17 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure

Group 2 (MIL-STD-810G)

Signal Pin

- Initial -----327.49 mOhms Max

Ground Pin

- Initial ----- 16.93 mOhms Max
- Shock & Vibration
 - <= +5.0 mOhms -----576 Points ----- Stable
 - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
 - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
 - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
 - +50.1 to +1000 mOhms ----- 0 Points ----- Unstable
 - >+1000 mOhms ----- 0 Points ----- Open Failure

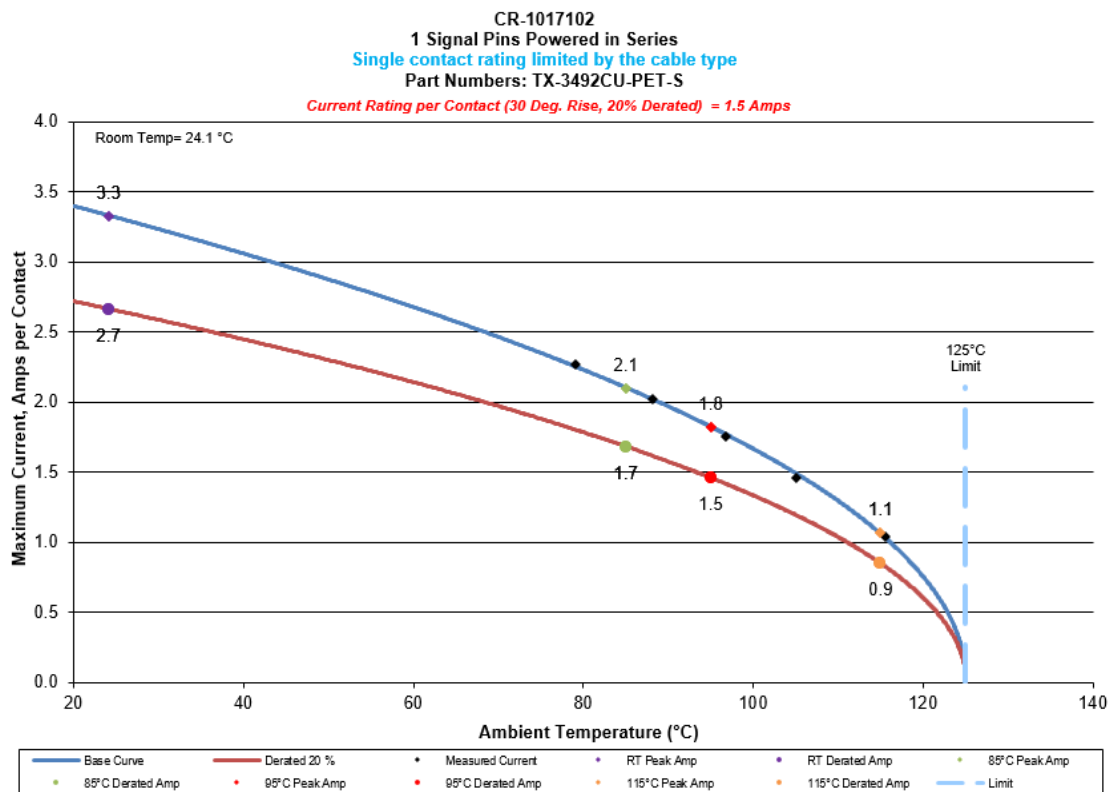
Mechanical Shock & Random Vibration:

- Shock
 - No Damage ----- Pass
 - 50 Nanoseconds ----- Pass
- Vibration
 - No Damage ----- Pass
 - 50 Nanoseconds ----- Pass

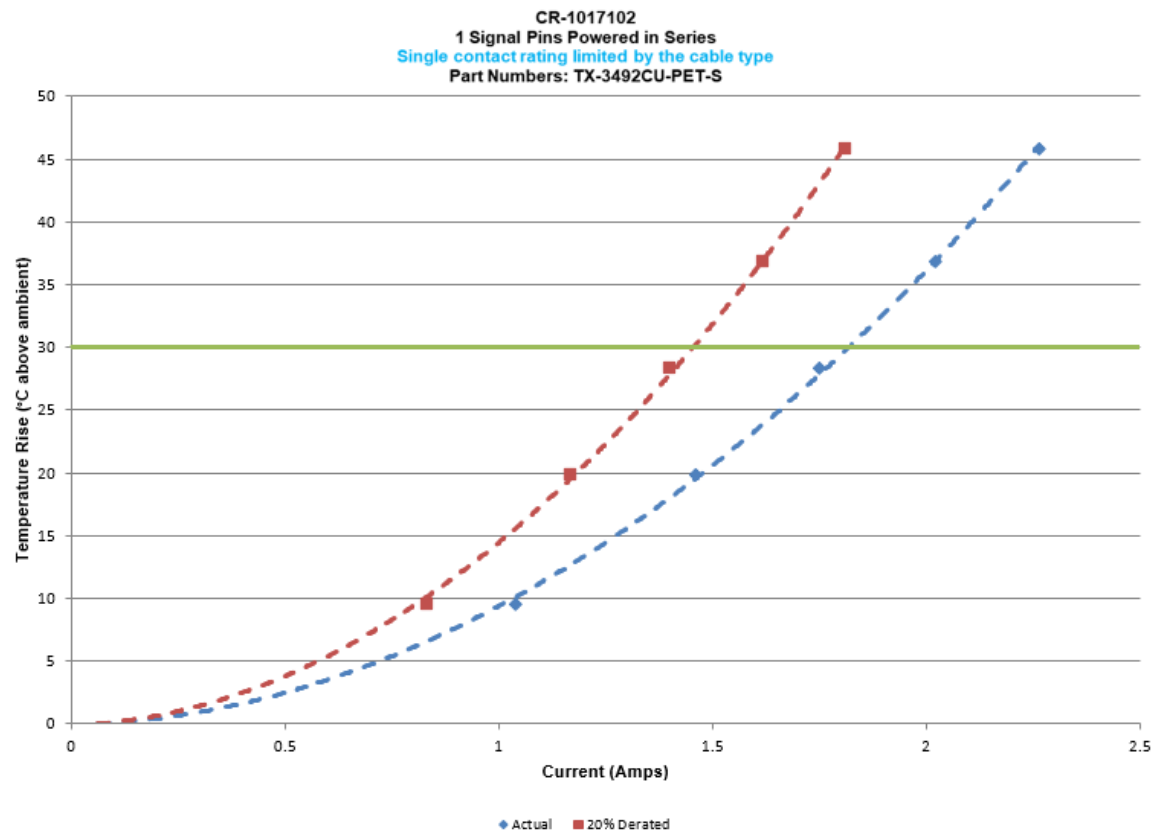
DATA SUMMARIES

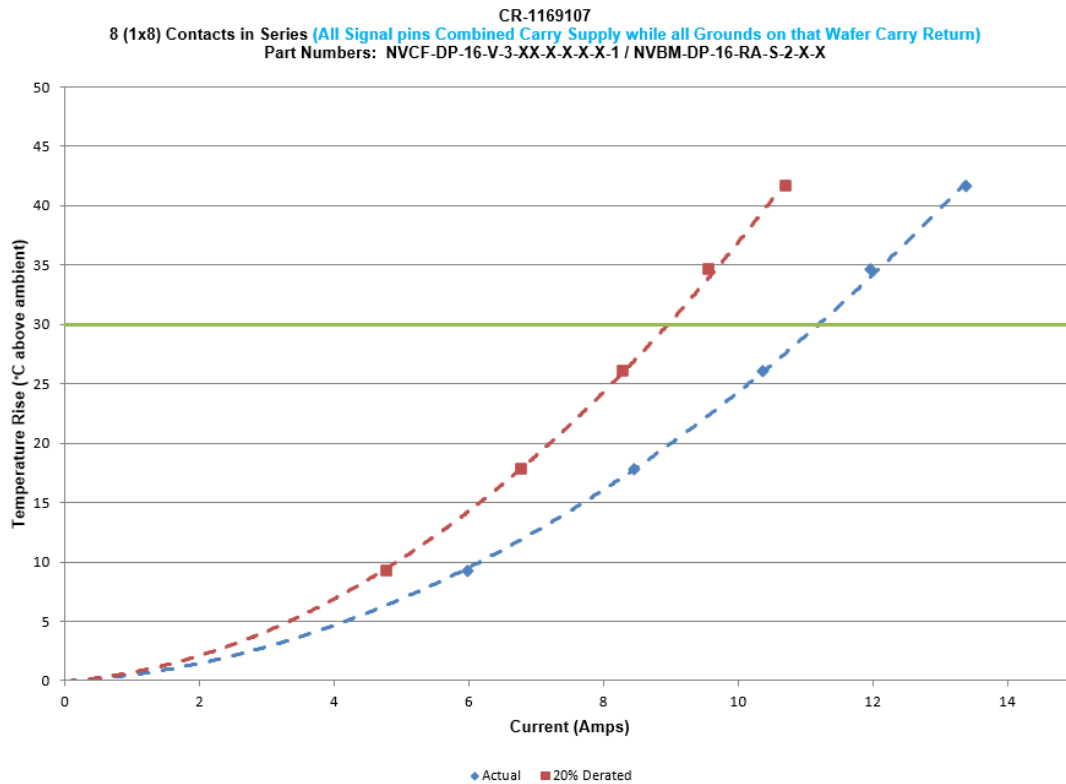
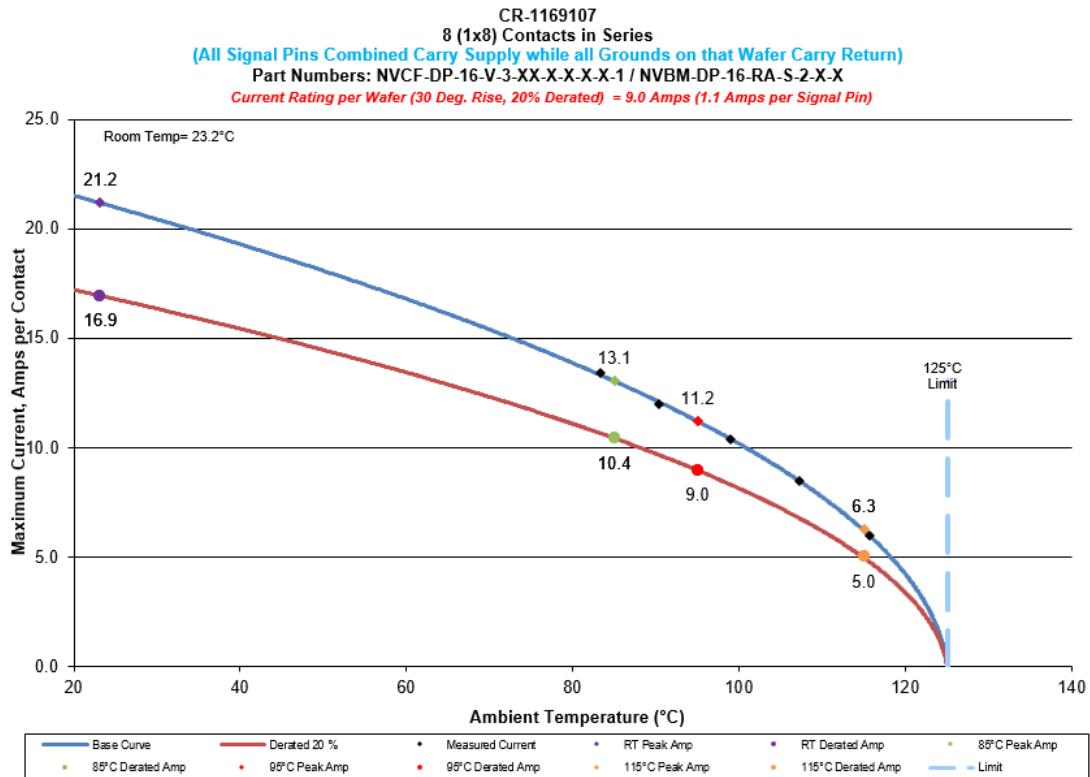
TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1° C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
 - a. Linear configuration with 1 adjacent conductors/contacts powered



DATA SUMMARIES Continued



DATA SUMMARIES Continued**b. Linear configuration with 8 adjacent conductors/contacts powered**

DATA SUMMARIES Continued

MATING/UNMATING:

Thermal Aging Group

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	42.97	9.66	31.05	6.98	27.80	6.25	26.15	5.88
Maximum	44.35	9.97	37.81	8.50	34.25	7.70	30.07	6.76
Average	43.60	9.80	33.63	7.56	30.55	6.87	27.64	6.22
St Dev	0.59	0.13	3.04	0.68	2.77	0.62	1.69	0.38
Count	4	4	4	4	4	4	4	4

Mating/Unmating Durability Group

	Initial				25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	40.03	9.00	29.40	6.61	41.37	9.30	33.72	7.58
Maximum	44.52	10.01	33.36	7.50	45.86	10.31	36.34	8.17
Average	41.69	9.37	30.92	6.95	44.06	9.91	34.81	7.83
St Dev	2.02	0.45	1.70	0.38	1.91	0.43	1.10	0.25
Count	4	4	4	4	4	4	4	4

	50 Cycles				75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	43.63	9.81	35.81	8.05	45.28	10.18	37.10	8.34
Maximum	47.90	10.77	38.34	8.62	50.08	11.26	39.50	8.88
Average	46.16	10.38	37.05	8.33	48.09	10.81	38.59	8.68
St Dev	1.80	0.41	1.05	0.24	2.16	0.49	1.08	0.24
Count	4	4	4	4	4	4	4	4

	100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)	Newtons	Force (Lbs)
Minimum	47.10	10.59	38.65	8.69	31.67	7.12	26.73	6.01
Maximum	52.75	11.86	41.10	9.24	33.54	7.54	28.11	6.32
Average	50.27	11.30	39.97	8.99	32.67	7.35	27.50	6.18
St Dev	2.39	0.54	1.17	0.26	0.77	0.17	0.60	0.13
Count	4	4	4	4	4	4	4	4

DATA SUMMARIES Continued

INSULATION RESISTANCE (IR):

Pin to Pin			
	Mated	Unmated	Unmated
Minimum	NVCF/NVBM	NVCF	NVBM
Initial	9000	Not Tested	9000
Thermal	9000	Not Tested	9000
Humidity	2060	Not Tested	3400

Pin to Ground			
	Mated	Unmated	Unmated
Minimum	NVCF/NVBM	NVCF	NVBM
Initial	9000	Not Tested	9000
Thermal	9000	Not Tested	9000
Humidity	9000	Not Tested	1200

Row to Row			
	Mated	Unmated	Unmated
Minimum	NVCF/NVBM	NVCF	NVBM
Initial	9000	Not Tested	9000
Thermal	9000	Not Tested	9000
Humidity	9000	Not Tested	9000

DIELECTRIC WITHSTANDING VOLTAGE (DWV):

Voltage Rating Summary	
Minimum	NVCF/NVBM
Break Down Voltage	600
Test Voltage	450
Working Voltage	150

Pin to Pin	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After Thermal Test Voltage	Passed
After Humidity Test Voltage	Passed

DATA SUMMARIES Continued

Cable Pull Force: 0° Pull

	Force (lbs)
Minimum	273.00
Maximum	317.80
Average	298.42

90° Pull Lateral

	Force (lbs)
Minimum	395.30
Maximum	445.10
Average	416.90

90° Pull Transverse

	Force (lbs)
Minimum	219.50
Maximum	222.10
Average	221.18

DATA SUMMARIES Continued

Cable Flex:

Lateral

Insulation Resistance minimums, IR

Voltage Rating Summary	
Minimum	
Test Voltage	450

Pin to Pin	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Dielectric Withstanding Voltage minimums, DWV

Voltage Rating Summary	
Minimum	
Test Voltage	450

Pin to Pin	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

DATA SUMMARIES Continued

Transverse

Insulation Resistance minimums, IR

Voltage Rating Summary	
Minimum	
Test Voltage	450

Pin to Pin	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Dielectric Withstanding Voltage minimums, DWV

Voltage Rating Summary	
Minimum	
Test Voltage	450

Pin to Pin	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Row to Row	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

Pin to Ground	
Initial Test Voltage	Passed
After 100 Flex Cycles Test Voltage	Passed

DATA SUMMARIES Continued

LLCR Durability:

- 1) A total of 576 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	3/14/2025	3/25/2025	4/4/2025	4/14/2025
Room Temp (Deg C)	22	22	22	22
Rel Humidity (%)	40	38	48	46
Technician	Tony Wagoner	Samuel Cecil	Tony Wagoner	Samuel Cecil
mOhm values	Actual	Delta	Delta	Delta
	Initial	Cycles	Therm Shck	Humidity
Pin Type: Signal 1				
Average	170.27	0.71	0.62	0.77
St. Dev.	50.2	0.56	0.61	0.61
Min	159.16	0.01	0	0.01
Max	179.72	3.89	4.27	4.43
Summary Count	512	512	512	512
Total Count	512	512	512	512
Pin Type: GND 1				
Average	10.97	0.42	0.66	0.6
St. Dev.	0.97	0.28	0.41	0.44
Min	9.63	0.01	0.05	0.02
Max	12.76	1.14	1.5	1.61
Summary Count	64	64	64	64
Total Count	64	64	64	64

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
Cycles	576	0	0	0	0	0
Therm Shck	576	0	0	0	0	0
Humidity	576	0	0	0	0	0

DATA SUMMARIES Continued

LLCR Thermal Aging:

- 1) A total of 576 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms:-----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms:-----Open Failure

LLCR Measurement Summaries by Pin Type			
Date	3/15/2025	4/1/2025	
Room Temp (Deg C)	22	22	
Rel Humidity (%)	40	39	
Technician	Tony Wagoner	Samuel Cecil	
mOhm values	Actual	Delta	
	Initial	Thermal	
Pin Type: Signal 1			
Average	170.5	3.07	
St. Dev.	4.87	2.68	
Min	161.12	0.01	
Max	180.09	13.9	
Summary Count	512	512	
Total Count	512	512	
Pin Type: GND 1			
Average	11.29	1.09	
St. Dev.	1.42	1.27	
Min	9.39	0.04	
Max	16.99	8.32	
Summary Count	64	64	
Total Count	64	64	

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
Thermal	456	118	2	0	0	0

DATA SUMMARIES Continued

LLCR Gas Tight:

- 1) A total of 1152 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms: -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

LLCR Measurement Summaries by Pin Type				
Date	1/22/2025	1/23/2025		
Room Temp (Deg C)	21	22		
Rel Humidity (%)	36	35		
Technician	Brian Stemle	Brian Stemle		
mOhm values	Actual	Delta		
	Initial	Acid Vapor		
Pin Type: Signal 1				
Average	173.06	0.73		
St. Dev.	7.81	0.66		
Min	152.93	0		
Max	189.25	5.19		
Summary Count	1024	1024		
Total Count	1024	1024		
Pin Type: GND 1				
Average	10.76	0.24		
St. Dev.	0.94	0.13		
Min	9.59	0		
Max	12.14	0.7		
Summary Count	128	128		
Total Count	128	128		

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	$>5 \text{ \& } \leq 10$	$>10 \text{ \& } \leq 15$	$>15 \text{ \& } \leq 50$	$>50 \text{ \& } \leq 1000$	>1000
Acid Vapor	1151	1	0	0	0	0

DATA SUMMARIES Continued

LLCR Shock & Vibration:

- 1). A total of 576 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
 - a. $\leq +5.0$ mOhms: -----Stable
 - b. $+5.1$ to $+10.0$ mOhms: -----Minor
 - c. $+10.1$ to $+15.0$ mOhms: -----Acceptable
 - d. $+15.1$ to $+50.0$ mOhms: -----Marginal
 - e. $+50.1$ to $+1000$ mOhms -----Unstable
 - f. $>+1000$ mOhms: -----Open Failure

Group 1

LLCR Measurement Summaries by Pin Type			
Date	4/1/2025	4/3/2025	
Room Temp (Deg C)	22	22	
Rel Humidity (%)	37	54	
Technician	Samuel Cecil	Sean Britt	
mOhm values	Actual	Delta	
	Initial	Shock-Vib	
Pin Type: Signal 1			
Average	318.75	1.39	
St. Dev.	5.94	1.25	
Min	305.08	0	
Max	331.61	7.93	
Summary Count	512	512	
Total Count	512	512	
Pin Type: GND 1			
Average	15.41	0.2	
St. Dev.	1.08	0.14	
Min	13.62	0	
Max	17.2	0.53	
Summary Count	64	64	
Total Count	64	64	

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	≤ 5	>5 & ≤ 10	>10 & ≤ 15	>15 & ≤ 50	>50 & ≤ 1000	>1000
Shock-Vib	559	17	0	0	0	0

DATA SUMMARIES Continued

Group 2(MIL-STD-810G)

LLCR Measurement Summaries by Pin Type			
Date	4/1/2025	4/4/2025	
Room Temp (Deg C)	22	22	
Rel Humidity (%)	37	48	
Technician	Samuel Cecil	Samuel Cecil	
mOhm values	Actual	Delta	
	Initial	Shock-Vib	
Pin Type: Signal 1			
Average	313.99	0.76	
St. Dev.	5.76	0.48	
Min	301.44	0.01	
Max	327.49	2.54	
Summary Count	512	512	
Total Count	512	512	
Pin Type: GND 1			
Average	14.91	0.27	
St. Dev.	1.04	0.29	
Min	13.28	0	
Max	16.93	1.19	
Summary Count	64	64	
Total Count	64	64	

LLCR Delta Count by Category						
	Stable	Minor	Acceptable	Marginal	Unstable	Open
mOhms	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
Shock-Vib	576	0	0	0	0	0

Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

Tracking Code: CR-1169107_Report_Rev_1	Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X
Part description: NVCF / NVBM	

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: TCT-04

Description: Dillon Quantrol TC21 25-1000 mm/min series test stand

Manufacturer: Dillon Quantrol

Model: TC2 I series test stand

Serial #: 04-1041-04

Accuracy: Speed Accuracy: +/- 5% of indicated speed; Speed Accuracy: +/- 5% of indicated speed;
... Last Cal: 05/29/2024, Next Cal: 05/29/2025

Equipment #: MO-11

Description: Switch/Multimeter

Manufacturer: Keithley

Model: 3706

Serial #: 120169

Accuracy: See Manual

... Last Cal: 09/11/2024, Next Cal: 09/11/2025

Equipment #: TSC-01

Description: Vertical Thermal Shock Chamber

Manufacturer: Cincinnati Sub Zero

Model: VTS-3-6-6-SC/AC

Serial #: 10-VT14993

Accuracy: See Manual

... Last Cal: 06/30/2024, Next Cal: 06/30/2025

Equipment #: THC-05

Description: Temperature/Humidity Chamber (Chamber Room)

Manufacturer: Thermotron

Model: SM-8-3800

Serial #: 05 23 00 02

Accuracy: See Manual

... Last Cal: 11/14/2024, Next Cal: 05/31/2025

Equipment #: HPT-01

Description: Hipot Safety Tester

Manufacturer: Vitrek

Model: V73

Serial #: 019808

Accuracy:

... Last Cal: 05/15/2024, Next Cal: 05/15/2025

Equipment #: SVC-01

Description: Shock & Vibration Table

Manufacturer: Data Physics

Model: LE-DSA-10-20K

Serial #: 10037

Accuracy: See Manual

... Last Cal: 11/31/2024, Next Cal: 11/31/2025

Tracking Code: CR-1169107_Report_Rev_1	Part #: NVCF-DP-16-V-3-XX-X-X-X-X-1/ NVBM-DP-16-RA-S-2-X-X
Part description: NVCF / NVBM	

EQUIPMENT AND CALIBRATION SCHEDULES

Equipment #: ACLM-01

Description: Accelerometer

Manufacturer: PCB Piezotronics

Model: 352C03

Serial #: 115819

Accuracy: See Manual

... Last Cal: 07/09/2024, Next Cal: 07/09/2025

Equipment #: ED-03

Description: Event Detector

Manufacturer: Analysis Tech

Model: 32EHD

Serial #: 1100604

Accuracy: See Manual

... Last Cal: 06/04/2024, Next Cal: 06/04/2025